Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.			
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EXAMINER DOCUMENT DATE NUMBER			NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
11/0	AA	4,792,958	12/20/88	OHBA, et al.	372	45		
	AB	4,809,287	02/28/89	OHBA, et al.	310	45		
	AC	4,835,117	05/30/89	OHBA, et al.	439	40		
	AD	4,949,349	08/14/90	OHBA, et al.	292	45		
	AE	4,910,743	03/20/90	OHBA, et al.	312	45	\	
	AF	4,928,285	05/22/90	KUSHIBE, et al.	312	45		
	AG	4,893,313	01/09/90	HATAKOSHI, et al.	272	46		
	AH	5,076,800	12/31/91	MILNES, et al.	429	394		
	Al	5,036,521	07/30/91	HATAKOSHI, et al.	562	307		
<b></b>	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	501	0/		
<b> </b>	AK	5,042,043	08/20/91	HATANO, et al.	421	72		
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257	13	<del></del>	
<del>                                     </del>	AM		01/07/92	HATANO, et al.	110	102		
2/2	AN	5,079,184 5,103,271	04/07/92	IZUMIYA, et al.	2517	94	<del></del>	
XIV	AN	3,103,271	·	REIGN PATENT DOCUMENTS	057	1 7 1		
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
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		OTHER RE	FERENCES (	Including Author, Title, Date, Pertinen	t Pages, e	tc.)		
		Y OHBA et al. Japan	ese Journal o	Applied Physics, Vol. 37 Part 2, No. 8A.	pp. L 905	- L 906, °F	ABRICATION AND	
	AW CHARACTERIZATION OF AIGAN/Gan DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING							
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EXAMINER INITIAL			NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
L-V.,		AA	5,228,044	07/13/93	ОНВА	372	45	4		
		AB	5,235,194	08/10/93	IZUMIYA, et al.	135.7	12			
L		AC	5,273,933	12/28/93	HATANO, et al.	117	89			
		AD	5,317,167	05/31/94	IZUMIYA, et al.	<u>asi</u>	13			
1		AE	5,432,808	07/11/95	HATANO, et al.	392	45	\		
		AF	5,617,438	04/01/97	HATANO, et al.	372	45			
		AG	5,740,192	04/14/98	HATANO, et al.	372	45			
		AH	5,998,810	12/07/99	HATANO, et al.	257	102	\		
		Al	6,242,764	06/05/01	Y. OHBA, et al.	257	190			
	1	AJ	5,990,495	11/23/99	Y. OHBA	257	94			
	<del>                                     </del>	AK	5,656,832	06/01/99	Y. OHBA, et al.	2<7	190			
	1		-5,909,040	06/01/99	Y. OHBA, et al.	257	190			
10		AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103			
<i>V</i>	$\sim$	AN	0,520,400		1. O(107, 0.ca).	as 1	100			
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		AZ	Additional References sheet(s)				erences sheet(s) attached			
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91	AA	5,146,465	09/92	KHAN, et al.	585	516			
3 /	AB	6,259,122	07/01	OTA, et al.	257	101			
	AC	5,875,052	02/99	SHMAGIN, et al.	359	244			
	AD	6,306,672 B1	10/01	KIM	438	22			
	AE	.6,046,464	04/00	SCHETZINA	259	96			
	AF	6,440,823 B1	08/02	VAUDO, et al.	438	408			
	AG	5,929,467	07/99	KAWAI, et al.	257	192			
MY	AH	5,923,058	07/99	AGARWAL, et al.	257	199			
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